

## Transaction Information

ToolId	56G4705AB
ToolStatus	Connected Idle
Location	Burlington
WaferSize	NA
FabSection	Failure Analysis

## General Product Information

VendorSupplier	FEI/Micrion
Model	Micrion 2500
Vintage	2003
SerialNo	M2051
AssetDescription	
SoftwareVersion	
CIM	
Process	Focused Ion Beam

## Hardware Configuration (Fab)

SystemType	Description	Quantity	Status
Main System	FIB Tool with sample chamber, gas modules and controller system.		OK
Factory Interface	NONE		
Handler System	Sample holder for smaller than 200mm		OK
Options System	NPVE FIB Assist Upgrade		OK
Others			

## Hardware Configuration (Subfab / Auxilliary Units)

Description	Quantity	Status
N/A		

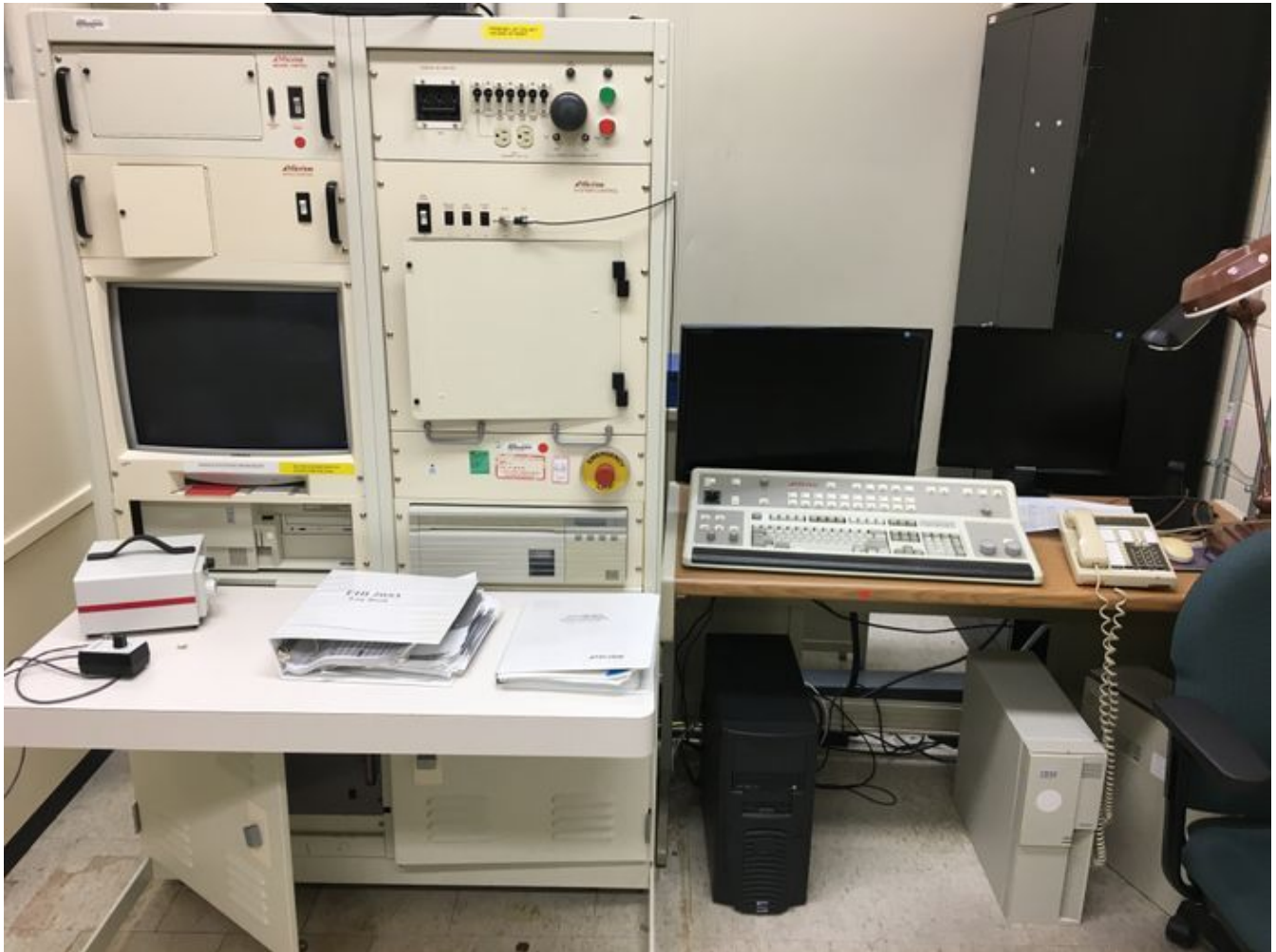
## Missing/Faulty Parts / Accesories List

Description	Quantity
N/A	

# Tool Pictures

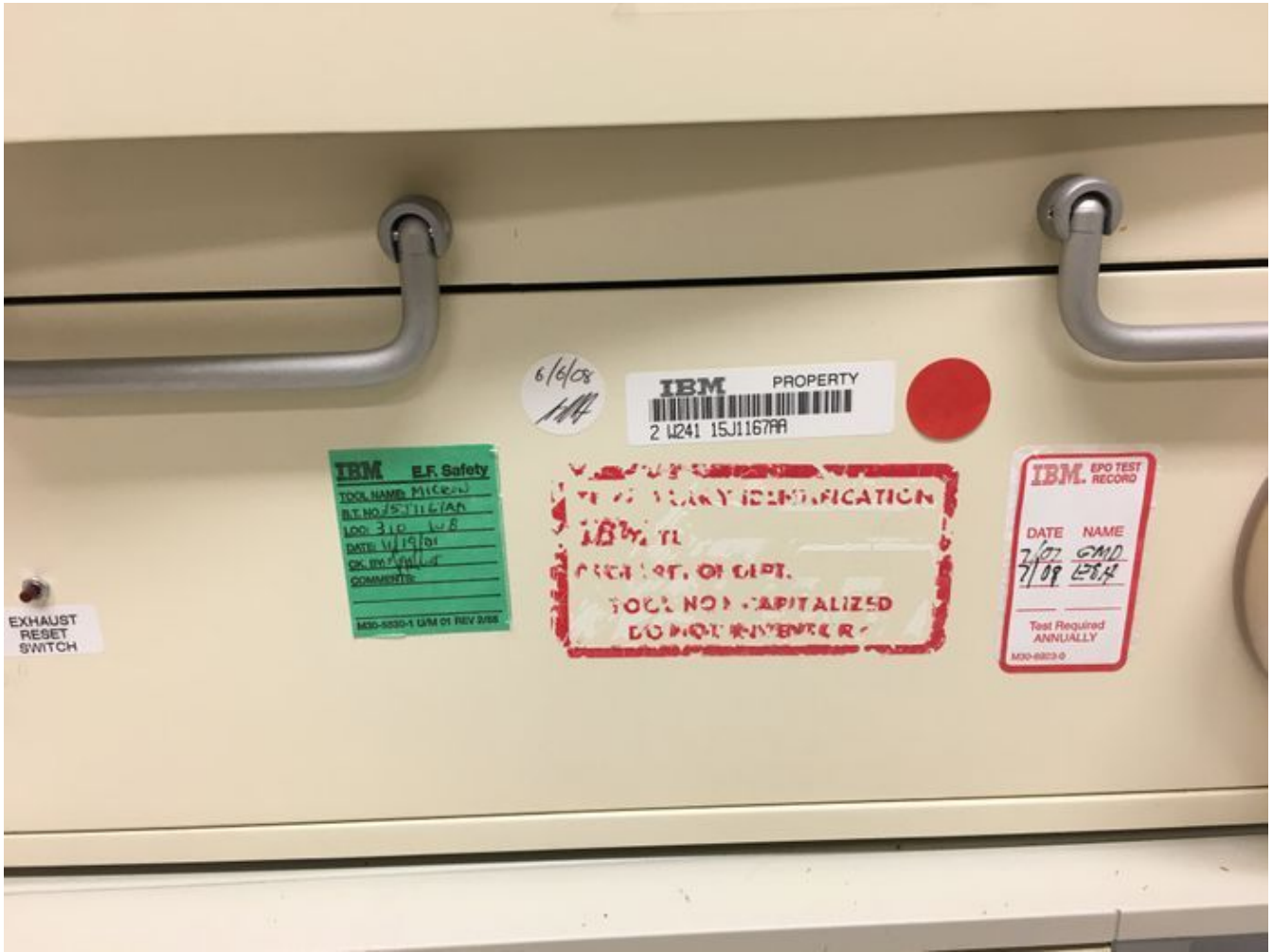
general

Uploaded



general

Uploaded



general

Uploaded



general

Uploaded



## Additional Configuration Files